

## WHAT IS CLAIMED IS:

1. A method of manufacturing a code address memory cell, comprising the steps of:
  - 5 forming a gate insulating film in which a plurality of oxide films and nitride films are stacked on a semiconductor substrate;  
forming a polysilicon film on said gate insulating film;  
etching given regions of said polysilicon film and said gate insulating film to form a gate; and
  - 10 performing impurity ion implantation process to form a source region and a drain region.
2. The method manufacturing a code address memory cell as claimed in claim 1, wherein said gate insulating film is formed of at least two or more  
15 layers of said oxide film and said insulating film are stacked.
3. The method manufacturing a code address memory cell as claimed in claim 1, wherein said gate insulating film is 30 ~ 300 Å in thickness.
- 20 4. The method manufacturing a code address memory cell as claimed in claim 1, wherein said gate insulating film is formed by stacking a first oxide film, a nitride film and a second oxide film.
5. The method manufacturing a code address memory cell as claimed in

claim 1, wherein said gate insulating film is formed by stacking a first oxide film, a first nitride film, a second oxide film and a second nitride film.

6. The method manufacturing a code address memory cell as claimed in  
5 claim 1, wherein said gate insulating film is formed by stacking a first oxide film, a first nitride film, a second oxide film, a second nitride film and a third oxide film.

7. A method of manufacturing a code address memory cell, comprising  
10 the steps of:

forming a device isolation film in a given region on a semiconductor substrate to define an active region and a device isolation region;

defining said active region into a cell region and a peripheral circuit region by a given process;

15 forming a tunnel oxide film and a first polysilicon film on the entire structure and then patterning said tunnel oxide film and said first polysilicon film so that said tunnel oxide film and said first polysilicon film can only remain in a given region of said cell region, thus defining a floating gate;

forming an insulating film in which said oxide film and said nitride  
20 film are stacked on the entire structure to form a second polysilicon film;

patterning said second polysilicon film and said insulating film so that they can remain only in a given region of said cell region and said peripheral circuit region, thus forming a control gate in said cell region a gate in said peripheral circuit region; and

performing an impurity ion implantation process for a given region of said semiconductor substrate to form a source region and a drain region, so that a flash memory cell is formed in said cell region and a code address memory cell is formed in said peripheral circuit region.

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8. The method manufacturing a code address memory cell as claimed in claim 7, wherein said insulating film is formed of at least two or more layers of said oxide film and said insulating film are stacked.

10 9. The method manufacturing a code address memory cell as claimed in claim 7, wherein said insulating film is 30 ~ 300 Å in thickness.

15 10. The method manufacturing a code address memory cell as claimed in claim 7, wherein said insulating film is formed by stacking a first oxide film, a nitride film and a second oxide film.

11. The method manufacturing a code address memory cell as claimed in claim 7, wherein said insulating film is formed by stacking a first oxide film, a first nitride film, a second oxide film and a second nitride film.

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12. The method manufacturing a code address memory cell as claimed in claim 7, wherein said insulating film is formed by stacking a first oxide film, a first nitride film, a second oxide film, a second nitride film and a third oxide film.